# Infineon Technologies - MB96F622RBPMC1-GSE2 Datasheet

Welcome to **E-XFL.COM** 

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Obsolete
Core Processor	F <sup>2</sup> MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I <sup>2</sup> C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	52
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f622rbpmc1-gse2

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



#### ■A/D converter

- □ SAR-type
- □ 8/10-bit resolution
- □ Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
- □ Range Comparator Function

#### ■ Source Clock Timers

Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)

#### ■ Hardware Watchdog Timer

- □ Hardware watchdog timer is active after reset
- □ Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval

#### ■Reload Timers

- □ 16-bit wide
- □ Prescaler with 1/2<sup>1</sup>, 1/2<sup>2</sup>, 1/2<sup>3</sup>, 1/2<sup>4</sup>, 1/2<sup>5</sup>, 1/2<sup>6</sup> of peripheral clock frequency
- □ Event count function

#### ■Free-Running Timers

- □ Signals an interrupt on overflow, supports timer clear upon match with Output Compare (0, 4)
- □ Prescaler with 1, 1/2<sup>1</sup>, 1/2<sup>2</sup>, 1/2<sup>3</sup>, 1/2<sup>4</sup>, 1/2<sup>5</sup>, 1/2<sup>6</sup>, 1/2<sup>7</sup>, 1/2<sup>8</sup> of peripheral clock frequency

## ■Input Capture Units

- □ 16-bit wide
- □ Signals an interrupt upon external event
- □ Rising edge, Falling edge or Both (rising & falling) edges sensitive

## ■Output Compare Units

- □ 16-bit wide
- □ Signals an interrupt when a match with Free-running Timer occurs
- ☐ A pair of compare registers can be used to generate an output signal

#### ■Programmable Pulse Generator

- □ 16-bit down counter, cycle and duty setting registers
- ☐ Can be used as 2 x 8-bit PPG
- □ Interrupt at trigger, counter borrow and/or duty match
- □ PWM operation and one-shot operation
- □ Internal prescaler allows 1, 1/4, 1/16, 1/64 of peripheral clock as counter clock or of selected Reload timer underflow as clock input
- ☐ Can be triggered by software or reload timer
- ☐ Can trigger ADC conversion
- ☐ Timing point capture

#### ■ Quadrature Position/Revolution Counter (QPRC)

- □ Up/down count mode, Phase difference count mode, Count mode with direction
- □ 16-bit position counter
- □ 16-bit revolution counter
- ☐ Two 16-bit compare registers with interrupt
- □ Detection edge of the three external event input pins AIN, BIN and ZIN is configurable

#### ■ Real Time Clock

- □ Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
- □ Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
- □ Read/write accessible second/minute/hour registers
- □ Can signal interrupts every half second/second/minute/hour/day
- □ Internal clock divider and prescaler provide exact 1s clock

#### ■External Interrupts

- □ Edge or Level sensitive
- □ Interrupt mask bit per channel
- □ Each available CAN channel RX has an external interrupt for wake-up
- □ Selected USART channels SIN have an external interrupt for wake-up

#### ■Non Maskable Interrupt

- □ Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
- □ Once enabled, can not be disabled other than by reset
- ☐ High or Low level sensitive
- ☐ Pin shared with external interrupt 0

#### ■I/O Ports

- ☐ Most of the external pins can be used as general purpose I/O
- ☐ All push-pull outputs (except when used as I<sup>2</sup>C SDA/SCL line)
- ☐ Bit-wise programmable as input/output or peripheral signal
- ☐ Bit-wise programmable input enable
- ☐ One input level per GPIO-pin (either Automotive or CMOS hysteresis)
- ☐ Bit-wise programmable pull-up resistor

#### ■Built-in On Chip Debugger (OCD)

- □ One-wire debug tool interface
- □ Break function:
  - Hardware break: 6 points (shared with code event)
  - · Software break: 4096 points

## □ Event function

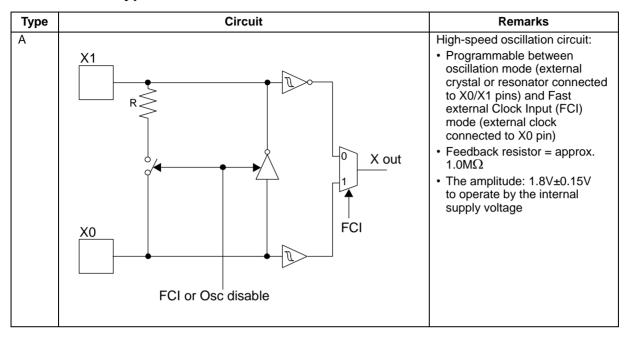
- Code event: 6 points (shared with hardware break)
- Data event: 6 points
- Event sequencer: 2 levels + reset
- □ Execution time measurement function
- ☐ Trace function: 42 branches
- □ Security function

#### ■Flash Memory

- □ Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
- Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
- □ Supports automatic programming, Embedded Algorithm
- □ Write/Erase/Erase-Suspend/Resume commands
- ☐ A flag indicating completion of the automatic algorithm
- $\hfill\square$  Erase can be performed on each sector individually
- □ Sector protection
- ☐ Flash Security feature to protect the content of the Flash
- □ Low voltage detection during Flash erase or write



# 6. I/O Circuit Type





Туре	Circuit	Remarks
K	Pull-up control	CMOS level output     (I <sub>OL</sub> = 4mA, I <sub>OH</sub> = -4mA)     Automotive input with input
	P-ch P-ch Pout	shutdown function • Programmable pull-up resistor • Analog input
	N-ch Nout	
	Standby control Automotive input for input shutdown	
	Analog input	
M	Pull-up control	CMOS level output (I <sub>OL</sub> = 4mA, I <sub>OH</sub> = -4mA) CMOS hysteresis input with input shutdown function Programmable pull-up resistor
	P-ch P-ch Pout  N-ch Nout  Hysteresis input	
	Standby control VVV To	
N	P-ch P-ch Pout	<ul> <li>CMOS level output         (I<sub>OL</sub> = 3mA, I<sub>OH</sub> = -3mA)</li> <li>CMOS hysteresis input with input shutdown function</li> <li>Programmable pull-up resistor</li> <li>*: N-channel transistor has slew rate control according to I<sup>2</sup>C</li> </ul>
	N-ch Nout*  Hysteresis input	spec, irrespective of usage.
	Standby control for input shutdown	



Туре	Circuit	Remarks
0	Standby control for input shutdown	Open-drain I/O Output 25mA, Vcc = 2.7V TTL input



# 9. User ROM Memory Map For Flash Devices

		MB96F622	MB96F623	MB96F625	
CPU mode address	Flash memory mode address	Flash size 32.5KB + 32KB	Flash size 64.5KB + 32KB	Flash size 128.5KB + 32KB	
FF:FFF <sub>H</sub> FF:8000 <sub>H</sub> FF:7FFF <sub>H</sub>	3F:FFF <sub>H</sub> 3F:8000 <sub>H</sub> 3F:7FFF <sub>H</sub>	SA39 - 32KB	SA39 - 64KB	SA39 - 64KB	
FF:0000 <sub>H</sub>	3F:0000 <sub>H</sub> 3E:FFFF <sub>H</sub>				Bank A of Flash A
FE:0000 <sub>H</sub>	3E:0000 <sub>н</sub>			SA38 - 64KB	
FD:FFFF <sub>H</sub>		Reserved	Reserved	Reserved	
DF:9FFF <sub>H</sub> DF:8000 <sub>H</sub>	1F:9FFF <sub>H</sub> 1F:8000 <sub>H</sub>	SA4 - 8KB	SA4 - 8KB	SA4 - 8KB	
DF:7FFF <sub>H</sub> DF:6000 <sub>H</sub>	1F:7FFF <sub>H</sub> 1F:6000 <sub>H</sub>	SA3 - 8KB	SA3 - 8KB	SA3 - 8KB	Death Def Flori
DF:5FFF <sub>H</sub> DF:4000 <sub>H</sub>	1F:5FFF <sub>H</sub> 1F:4000 <sub>H</sub>	SA2 - 8KB	SA2 - 8KB	SA2 - 8KB	Bank B of Flash A
DF:3FFF <sub>H</sub> DF:2000 <sub>H</sub>	1F:3FFF <sub>H</sub> 1F:2000 <sub>H</sub>	SA1 - 8KB	SA1 - 8KB	SA1 - 8KB	
DF:1FFF <sub>H</sub> DF:0000 <sub>H</sub>	1F:1FFF <sub>H</sub> 1F:0000 <sub>H</sub>	SAS - 512B*	SAS - 512B*	SAS - 512B*	Bank A of Flash A
DE:FFFF <sub>H</sub> DE:0000 <sub>H</sub>		Reserved	Reserved	Reserved	

<sup>\*:</sup> Physical address area of SAS-512B is from DF:0000 $_{\rm H}$  to DF:01FF $_{\rm H}$ . Others (from DF:0200 $_{\rm H}$  to DF:1FFF $_{\rm H}$ ) is mirror area of SAS-512B. Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000 $_{\rm H}$  -DF:01FF $_{\rm H}$ . SAS can not be used for E $^2$ PROM emulation.



#### ■Precautions Related to Usage of Devices

Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

## 12.2 Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress's recommended conditions. For detailed information about mount conditions, contact your sales representative.

## ■Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

#### ■Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. Cypress recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with Cypress ranking of recommended conditions.

## ■Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

## ■ Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- 1. Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.
  - When you open Dry Package that recommends humidity 40% to 70% relative humidity.
- 3. When necessary, Cypress packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- 4. Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

## ■Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the Cypress recommended conditions for baking.

Condition: 125°C/24 h



# 13. Handling Devices

## Special care is required for the following when handling the device:

- · Latch-up prevention
- · Unused pins handling
- · External clock usage
- · Notes on PLL clock mode operation
- Power supply pins (V<sub>cc</sub>/V<sup>ss</sup>)
- · Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- · Pin handling when not using the A/D converter
- · Notes on Power-on
- · Stabilization of power supply voltage
- · Serial communication
- Mode Pin (MD)

## 13.1 Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V<sub>CC</sub> or lower than V<sub>SS</sub> is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between V<sub>cc</sub> pins and V<sub>ss</sub> pins.
- The AV<sub>CC</sub> power supply is applied before the V<sub>CC</sub> voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device.

For the same reason, extra care is required to not let the analog power-supply voltage (AV<sub>CC</sub>, AVRH) exceed the digital power-supply voltage.

#### 13.2 Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than  $2k\Omega$ .

Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.



## 13.6 Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

## 13.7 Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AV<sub>CC</sub>, AVRH) and analog inputs (ANn) on after turning the digital power supply (V<sub>CC</sub>) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, AVRH must not exceed  $AV_{CC}$ . Input voltage for ports shared with analog input ports also must not exceed  $AV_{CC}$  (turning the analog and digital power supplies simultaneously on or off is acceptable).

## 13.8 Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as  $AV_{CC} = V_{CC}$ ,  $AV_{SS} = AVRH = V_{SS}$ .

#### 13.9 Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than 50µs from 0.2V to 2.7V.

## 13.10Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the  $V_{CC}$  power supply voltage, a malfunction may occur. The  $V_{CC}$  power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that  $V_{CC}$  ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard  $V_{CC}$  power supply voltage and the transient fluctuation rate becomes  $0.1V/\mu s$  or less in instantaneous fluctuation for power supply switching.

## 13.11 Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication.

Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

## 13.12Mode Pin (MD)

Connect the mode pin directly to Vcc or Vss pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to Vcc or Vss pin and provide a low-impedance connection.



## 14.2 Recommended Operating Conditions

 $(V_{SS} = AV_{SS} = 0V)$ 

Parameter	Symbol		Value		Unit	Remarks
Farameter	Syllibol	Min	Тур	Max	Ollic	Kemarks
Power supply	V <sub>CC</sub> , AV <sub>CC</sub>	2.7	-	5.5	V	
voltage	VCC, AVCC	2.0	-	5.5	V	Maintains RAM data in stop mode
Smoothing capacitor at C pin	Cs	0.5	1.0 to 3.9	4.7	μF	$\begin{array}{l} 1.0\mu F \text{ (Allowance within } \pm 50\%) \\ 3.9\mu F \text{ (Allowance within } \pm 20\%) \\ \text{Please use the ceramic capacitor or the capacitor of the frequency response of this level.} \\ \text{The smoothing capacitor at $V_{CC}$ must use the one of a capacity value that is larger than $C_{S}$.} \end{array}$

## **WARNING**

The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.



## 14.3 DC Characteristics

# 14.3.1 Current Rating

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$ 

D	0	Pin	0177		Value		1111	Damarka	
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks	
			PLL Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32MHz	-	25	-	mA	T <sub>A</sub> = +25°C	
	I <sub>CCPLL</sub>		Flash 0 wait	-	-	34	mA	T <sub>A</sub> = +105°C	
			(CLKRC and CLKSC stopped)	-	-	35	mA	T <sub>A</sub> = +125°C	
			Main Run mode with CLKS1/2 = CLKB = CLKP1/2 = 4MHz	-	3.5	-	mA	T <sub>A</sub> = +25°C	
	ICCMAIN		Flash 0 wait	-	-	7.5	mA	T <sub>A</sub> = +105°C	
			(CLKPLL, CLKSC and CLKRC stopped)	-	-	8.5	mA	T <sub>A</sub> = +125°C	
			RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 2MHz		1.7	-	mA	T <sub>A</sub> = +25°C	
Power supply current in Run modes <sup>*1</sup>	I <sub>CCRCH</sub>	Vcc	Flash 0 wait	-	-	5.5	mA	T <sub>A</sub> = +105°C	
			(CLKMC, CLKPLL and CLKSC stopped)	-	-	6.5	mA	T <sub>A</sub> = +125°C	
			RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC = 100kHz	-	0.15	-	mA	T <sub>A</sub> = +25°C	
	I <sub>CCRCL</sub>		Flash 0 wait	-	-	3.2	mA	T <sub>A</sub> = +105°C	
			(CLKMC, CLKPLL and CLKSC stopped)	-	-	4.2	mA	T <sub>A</sub> = +125°C	
			Sub Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32kHz		0.1	-	mA	T <sub>A</sub> = +25°C	
	I <sub>CCSUB</sub>		Flash 0 wait	-	-	3	mA	T <sub>A</sub> = +105°C	
			(CLKMC, CLKPLL and CLKRC stopped)	-	-	4	mA	T <sub>A</sub> = +125°C	

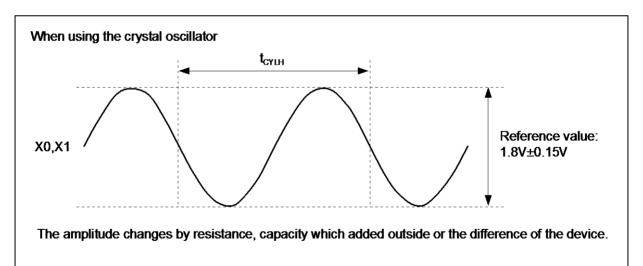


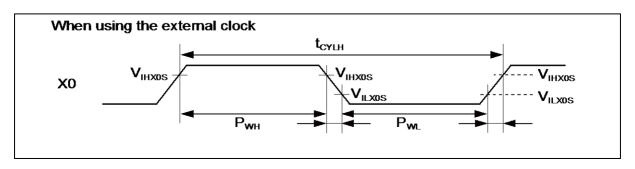
## 14.4 AC Characteristics

## 14.4.1 Main Clock Input Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, VD=1.8V\pm0.15V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$ 

				Value				
Parameter	Symbol	Pin name	Min	Тур	Max	Unit	Remarks	
			4	-	8	MHz	When using a crystal oscillator, PLL off	
Input frequency	f <sub>C</sub>	X0, X1	-	-	8	MHz	When using an opposite phase external clock, PLL off	
		XI	4	-	8	MHz	When using a crystal oscillator or opposite phase external clock, PLL on	
Input fraguancy	,		f V0	-	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL off
Input frequency	f <sub>FCI</sub> X0		4	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL on	
Input clock cycle	t <sub>CYLH</sub>	-	125	-	-	ns		
Input clock pulse width	P <sub>WH</sub> , P <sub>WL</sub>	-	55	-	-	ns		



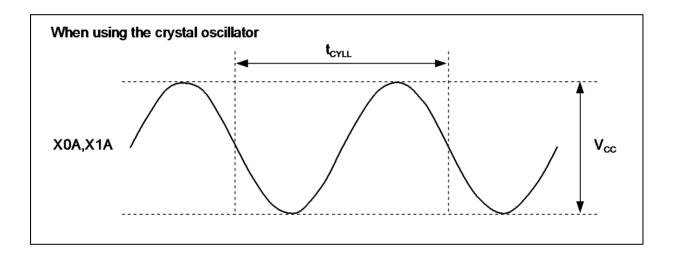


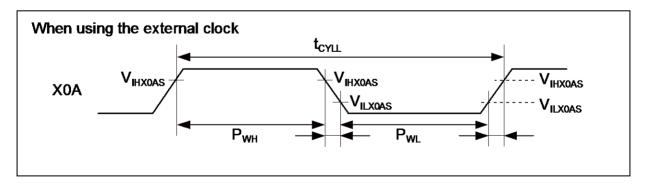


## 14.4.2 Sub Clock Input Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}\text{C to } + 125^{\circ}\text{C})$ 

Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks	
Farailleter	Symbol	name	Conditions	Min	Тур	Max	Oilit	Remarks	
		X0A,	-	-	32.768	-	kHz	When using an oscillation circuit	
Input frequency	f <sub>CL</sub>	f <sub>CL</sub>	X1A	-	-	-	100	kHz	When using an opposite phase external clock
				X0A	-	-	-	50	kHz
Input clock cycle	t <sub>CYLL</sub>	-	-	10	-	-	μS		
Input clock pulse width	-	-	P <sub>WH</sub> /t <sub>CYLL</sub> , P <sub>WL</sub> /t <sub>CYLL</sub>	30	-	70	%		







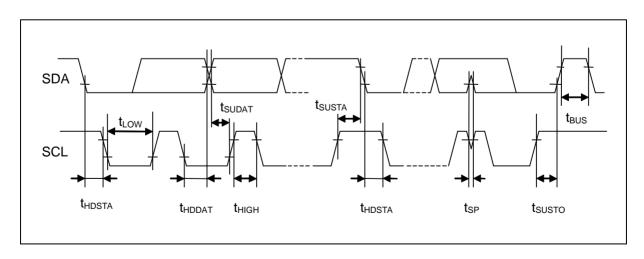
# 14.4.10 PC Timing

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C)$ 

Parameter	Parameter Symbol Co		Typica	al mode	High-spe	ed mode*4	Unit
Parameter	Symbol	Conditions	Min	Max	Min	Max	Unit
SCL clock frequency	f <sub>SCL</sub>		0	100	0	400	kHz
(Repeated) START condition hold							
time	t <sub>HDSTA</sub>		4.0	-	0.6	-	μS
$SDA \downarrow \rightarrow SCL \downarrow$							
SCL clock "L" width	t <sub>LOW</sub>		4.7	-	1.3	-	μS
SCL clock "H" width	t <sub>HIGH</sub>		4.0	-	0.6	-	μS
(Repeated) START condition setup							
time	t <sub>SUSTA</sub>		4.7	-	0.6	-	μS
SCL ↑ → SDA ↓		$C_L = 50pF,$ $R = (Vp/I_{OL})^{*1}$					
Data hold time	t <sub>HDDAT</sub>	$R = (Vp/I_{OL})^{*}$	0	3.45* <sup>2</sup>	0	0.9*3	μS
$SCL \downarrow \rightarrow SDA \downarrow \uparrow$	THODAI		U	J. <del>1</del> J	O	0.9	μδ
Data setup time	t		250	1_	100	_	ns
$SDA \downarrow \uparrow \rightarrow SCL \uparrow$	t <sub>SUDAT</sub>		230	_	100	_	113
STOP condition setup time	4		4.0	_	0.6	_	
$\operatorname{SCL} \uparrow \to \operatorname{SDA} \uparrow$	tsusto		4.0	-	0.6	-	μS
Bus free time between							
"STOP condition" and	t <sub>BUS</sub>		4.7	-	1.3	-	μS
"START condition"							
Dulco width of onikes which will be				(1.1.5)		(4.4.5)	
Pulse width of spikes which will be suppressed by input noise filter	t <sub>SP</sub>	-	0	(1-1.5) ×	0	(1-1.5) ×	ns
Suppressed by input hoise litter				t <sub>CLKP1</sub> *°		t <sub>CLKP1</sub> *°	

 $<sup>^{\</sup>star 1}$ : R and C<sub>L</sub> represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and I<sub>OL</sub> indicates V<sub>OL</sub> guaranteed current.

<sup>\*5:</sup> t<sub>CLKP1</sub> indicates the peripheral clock1 (CLKP1) cycle time.



 $<sup>^{\</sup>star 2}$ : The maximum  $t_{HDDAT}$  only has to be met if the device does not extend the "L" width  $(t_{LOW})$  of the SCL signal.

<sup>\*3:</sup> A high-speed mode I<sup>2</sup>C bus device can be used on a standard mode I<sup>2</sup>C bus system as long as the device satisfies the requirement of "t<sub>SUDAT</sub> ≥ 250ns".

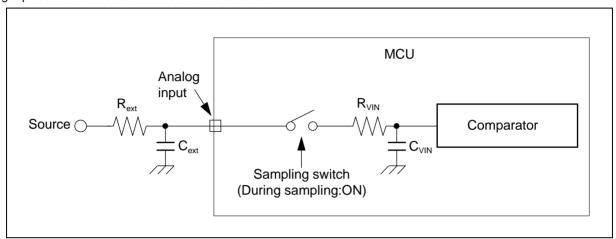
<sup>\*4:</sup> For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.



#### 14.5.2 Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (Tsamp) depends on the external driving impedance R<sub>ext</sub>, the board capacitance of the A/D converter input pin C<sub>ext</sub> and the AV<sub>CC</sub> voltage level. The following replacement model can be used for the calculation:



Rext: External driving impedance

Cext: Capacitance of PCB at A/D converter input

C<sub>VIN</sub>: Analog input capacity (I/O, analog switch and ADC are contained)

R<sub>VIN</sub>: Analog input impedance (I/O, analog switch and ADC are contained)

The following approximation formula for the replacement model above can be used: Tsamp =  $7.62 \times (\text{Rext} \times \text{Cext} + (\text{Rext} + \text{R}_{\text{VIN}}) \times \text{C}_{\text{VIN}})$ 

- Do not select a sampling time below the absolute minimum permitted value. (0.5 $\mu$ s for 4.5V  $\leq$  AV<sub>CC</sub>  $\leq$  5.5V, 1.2 $\mu$ s for 2.7V  $\leq$  AV<sub>CC</sub> < 4.5V)
- If the sampling time cannot be sufficient, connect a capacitor of about 0.1µF to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current IIL (static current before the sampling switch) or the analog input leakage current IAIN (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current IIL cannot be compensated by an external capacitor.
- The accuracy gets worse as |AVRH AV<sub>SS</sub>| becomes smaller.



## 14.5.3 Definition of A/D Converter Terms

• Resolution : Analog variation that is recognized by an A/D converter.

• Nonlinearity error : Deviation of the actual conversion characteristics from a straight line that connects the zero

transition point (0b0000000000  $\longleftrightarrow$  0b0000000001) to the full-scale transition point

 $(0b11111111110 \longleftrightarrow 0b1111111111).$ 

• Differential nonlinearity error : Deviation from the ideal value of the input voltage that is required to change the

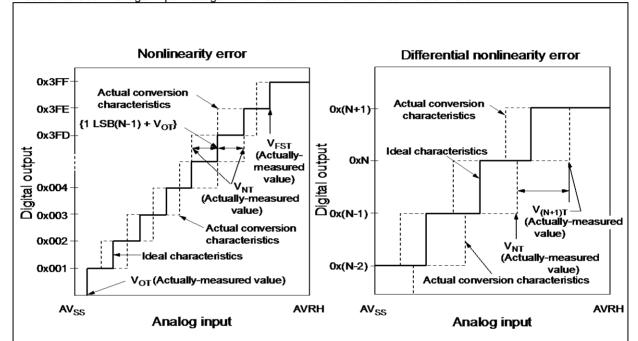
output code by 1LSB.

• Total error : Difference between the actual value and the theoretical value. The total error includes zero

transition error, full-scale transition error and nonlinearity error.

• Zero transition voltage : Input voltage which results in the minimum conversion value.

• Full scale transition voltage: Input voltage which results in the maximum conversion value.



Nonlinearity error of digital output N = 
$$\frac{V_{NT} - \{1LSB \times (N-1) + V_{OT}\}}{1LSB}$$
 [LSB]

Differential nonlinearity error of digital output N = 
$$\frac{V_{(N+1)T} - V_{NT}}{1LSB}$$
 - 1 [LSB]

$$1LSB = \frac{V_{FST} - V_{OT}}{1022}$$

N : A/D converter digital output value.

 $V_{OT}$  : Voltage at which the digital output changes from 0x000 to 0x001.  $V_{FST}$  : Voltage at which the digital output changes from 0x3FE to 0x3FF.  $V_{NT}$  : Voltage at which the digital output changes from 0x(N - 1) to 0xN.



## 14.6 Low Voltage Detection Function Characteristics

 $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}\text{C to } + 125^{\circ}\text{C})$ 

Parameter	Cymhal	Conditions		Value	Value				
Parameter	Symbol	Conditions	Min	Тур	Max	Unit			
	$V_{DL0}$	CILCR:LVL = 0000 <sub>B</sub>	2.70	2.90	3.10	V			
	$V_{DL1}$	CILCR:LVL = 0001 <sub>B</sub>	2.79	3.00	3.21	V			
	$V_{DL2}$	CILCR:LVL = 0010 <sub>B</sub>	2.98	3.20	3.42	V			
Detected voltage*1	$V_{DL3}$	CILCR:LVL = 0011 <sub>B</sub>	3.26	3.50	3.74	V			
	$V_{DL4}$	CILCR:LVL = 0100 <sub>B</sub>	3.45	3.70	3.95	V			
	$V_{DL5}$	CILCR:LVL = 0111 <sub>B</sub>	3.73	4.00	4.27	V			
	V <sub>DL6</sub>	CILCR:LVL = 1001 <sub>B</sub>	3.91	4.20	4.49	V			
Power supply voltage change rate <sup>2</sup>	dV/dt	-	- 0.004	-	+ 0.004	V/μs			
Lhustana sia usialdh		CILCR:LVHYS=0	-	-	50	mV			
Hysteresis width	Hysteresis width V <sub>HYS</sub>		80	100	120	mV			
Stabilization time	T <sub>LVDSTAB</sub>	-	-	-	75	μЅ			
Detection delay time	t <sub>d</sub>	-	-	-	30	μS			

<sup>&</sup>lt;sup>\*1</sup>: If the power supply voltage fluctuates within the time less than the detection delay time (t<sub>d</sub>), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

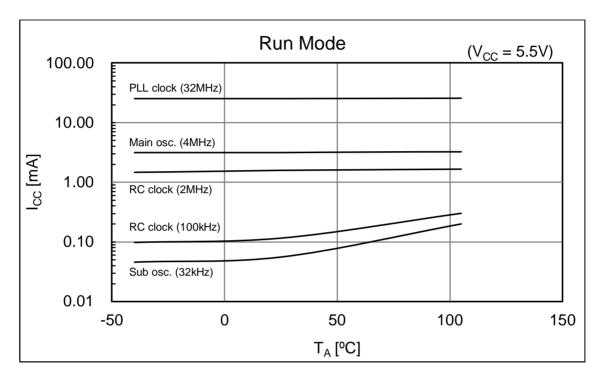
<sup>&</sup>lt;sup>\*2</sup>: In order to perform the low voltage detection at the detection voltage (V<sub>DLX</sub>), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.

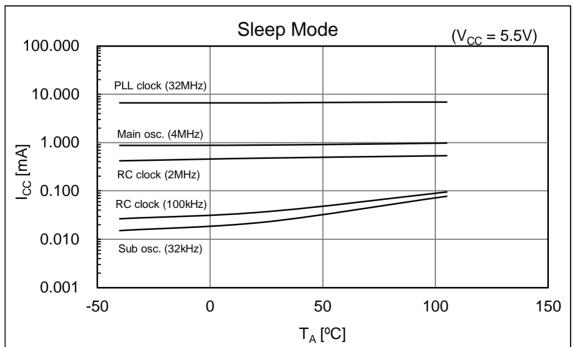


# 15. Example Characteristics

This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value.

## ■MB96F625



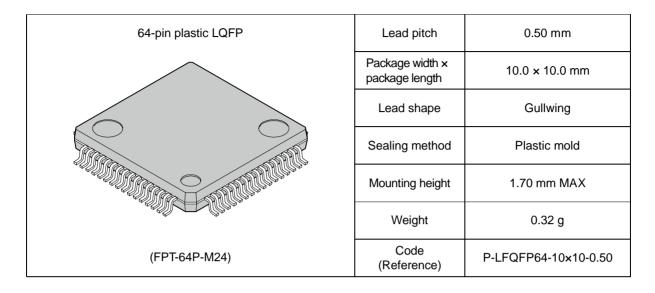


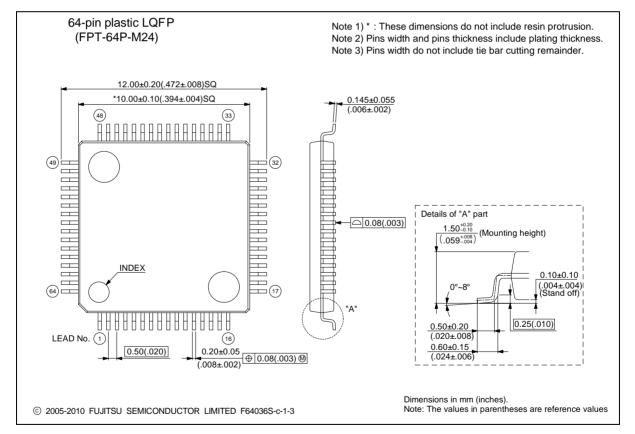


# ■Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 4MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 2MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 100kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
Timer mode	PLL	CLKMC = 4MHz, CLKPLL = 32MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode









Page	Section	Change Results
56	Electrical Characteristics 7. Flash Memory Write/Erase Characteristics	Changed the Note While the Flash memory is written or erased, shutdown of the external power (V <sub>CC</sub> ) is prohibited. In the application system where the external power (V <sub>CC</sub> ) might be shut down while writing, be sure to turn the power off by using an external voltage detector.
		While the Flash memory is written or erased, shutdown of the external power ( $V_{CC}$ ) is prohibited. In the application system where the external power ( $V_{CC}$ ) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.
60	Ordering Information	Deleted the Part number MCU with CAN controller MB96F622RBPMC-GTE2 MB96F622RBPMC1-GTE2 MB96F623RBPMC-GTE2 MB96F623RBPMC1-GTE2 MB96F625RBPMC1-GTE2 MB96F625RBPMC1-GTE2 MCU without CAN controller MB96F622ABPMC1-GTE2 MB96F622ABPMC1-GTE2 MB96F623ABPMC1-GTE2 MB96F623ABPMC1-GTE2 MB96F625ABPMC1-GTE2 MB96F625ABPMC1-GTE2 MB96F625ABPMC1-GTE2 MB96F625ABPMC1-GTE2
Revision 2	2.1	
-	-	Company name and layout design change

NOTE: Please see "Document History" about later revised information.